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APPLICATION NO. FILING DATE		FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/789,044	02/27/2004	Kie Y. Ahn	1303.070US2	8340
21186	7590 09/11/2006	EXAMINER		
SCHWEGM	AN, LUNDBERG, WO	MENZ, DOUGLAS M		
P.O. BOX 293	8			_
MINNEAPOLIS, MN 55402			ART UNIT	PAPER NUMBER
			2891	

DATE MAILED: 09/11/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application N	lo.	Applicant(s)			
Office Action Summary		10/789,044		AHN ET AL.			
		Examiner		Art Unit			
		Douglas M. Mo		2891			
- Period fo	- The MAILING DATE of this communication r Reply	appears on the co	ver sheet with the c	orrespondence ad	ddress		
WHIC - Extension - If NO - Failure Any re	DRTENED STATUTORY PERIOD FOR RE HEVER IS LONGER, FROM THE MAILING sions of time may be available under the provisions of 37 CFR SIX (6) MONTHS from the mailing date of this communication. period for reply is specified above, the maximum statutory per e to reply within the set or extended period for reply will, by state that the provision of the	DATE OF THIS ( R 1.136(a). In no event, he riod will apply and will expand the application of the riod will expand	COMMUNICATION owever, may a reply be tim ire SIX (6) MONTHS from in to become ABANDONE	N. nely filed the mailing date of this of			
Status							
1)	Responsive to communication(s) filed on 30	0 May 2006					
		This action is non-f	inal.				
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is						
	closed in accordance with the practice unde						
Dispositio	on of Claims						
5)□ - 6)⊠ - 7)□ -	Claim(s) <u>1-40</u> is/are pending in the application of the above claim(s) <u>5-40</u> is/are withdray Claim(s) is/are allowed. Claim(s) <u>1-4</u> is/are rejected. Claim(s) is/are objected to. Claim(s) are subject to restriction and	awn from consider					
Application	on Papers						
10)⊠ 1	The specification is objected to by the Examember the drawing(s) filed on 27 February 2004 is Applicant may not request that any objection to the Replacement drawing sheet(s) including the confirm oath or declaration is objected to by the	dare: a)⊠ accepto the drawing(s) be he rection is required if	eld in abeyance. See the drawing(s) is obj	e 37 CFR 1.85(a). ected to. See 37 C	FR 1.121(d).		
Priority u	nder 35 U.S.C. § 119						
12)	Acknowledgment is made of a claim for fore  All b) Some * c) None of:  1. Certified copies of the priority docume 2. Certified copies of the priority docume 3. Copies of the certified copies of the papplication from the International Buree the attached detailed Office action for a	ents have been re ents have been re priority documents reau (PCT Rule 17	ceived. ceived in Application have been receive '.2(a)).	on No ed in this National	l Stage		
2) 🔲 Notice 3) 🔯 Inform	(s) e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO/SB/08) No(s)/Mail Date <u>5/25/06</u> .	5) [	Interview Summary Paper No(s)/Mail Da Notice of Informal P Other:	ite			

#### **DETAILED ACTION**

## Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).

Claims 1-3 are rejected under 35 U.S.C. 103(a) as being unpatentable over VanDover (US 6093944) in view of Scobey et al. (US 6115401).

Regarding claim 1, VanDover discloses an electronic device comprising:

A substrate (Col. 4, line 24 - Col. 5, line 19); and

A dielectric layer disposed on the substrate (Col. 4, line 24 - Col. 5, line 19), the dielectric layer containing a  $\text{TiO}_2$  layer doped with a lanthanide (Col. 3, lines: 39-53 and Col. 5, lines: 21-48).

VanDover further discloses that the TiO<sub>2</sub> layer is formed by a reactive sputtering method and that other methods may be used, such as ion beam sputtering (Col. 8, lines: 30-39). However, VanDover does not explicitly disclose wherein the TiO<sub>2</sub> layer is formed by ion assisted electron beam evaporation.

Scobey discloses that dielectric layers of metal oxide materials can be produced by commercially known plasma deposition techniques, such as ion assisted electron beam evaporation and ion beam sputtering and further that both methods produce advantageously dense and stable materials (Col. 10, lines: 50-67).

Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention to form VanDover's TiO<sub>2</sub> layer by ion assisted electron beam evaporation, as taught by Scobey (Col. 10, lines: 50-67) instead of by ion beam sputtering, since Scobey explicitly teaches that ion assisted electron beam evaporation can be used in place of ion beam sputtering to produce metal oxide layers that are advantageously dense and stable (Col. 10, lines: 50-65).

Since oxygen is a constituent of TiOx, it is inherent that an oxygen content is supplemented during the formation process of the TiOx layer doped with the lanthanide.

Regarding claim 2, VanDover further discloses wherein the lanthanide has a concentration in the dielectric layer of between about 10% and about 30% of the dielectric layer (Col. 3, lines: 39-50).

Regarding claim 3, VanDover further discloses wherein the dielectric layer has a dielectric constant of greater than 45 (Col. 8, lines: 60-61), which would include applicant's claimed dielectric constant range of about 50 to about 110.

Claim 4 is rejected under 35 U.S.C. 103(a) as being unpatentable over VanDover (US 6093944) in view of Scobey et al. (US 6115401) as applied to claim 1 above, and further in view of Gardner et al. (US 6225168).

Regarding claim 4, VanDover in view of Scobey disclose the limitations of claim 1 as mentioned above, however they do not explicitly disclose that the dielectric layer has an equivalent oxide thickness ( $t_{eq}$ ) in the range from about 1.5 Angstroms to about 5 Angstroms.

Applicant specifically defines the term " $t_{eq}$ " on page 6, lines: 9-12 of the specification, which is further expressed by the mathematical relationship given on page 7 of the specification.

Using Applicant's definition and mathematical relationship, the Examiner has concluded that a t<sub>eq</sub> in the range from about 1.5 Angstroms to about 5 Angstroms would correspond to TiO<sub>2</sub> dielectric layer having a physical thickness range of about 17

Angstroms to about 57 Angstroms with a dielectric constant of 45, however, VanDover's dielectric constant can be greater than 45 (Col. 8, lines: 60-61). For example, if VanDover's dielectric constant is 100, then the physical thickness range would be about 38 Angstroms to about 128 Angstroms.

Therefore, in order to satisfy the limitation of claim 4, the Examiner must show a physical thickness of the TiO<sub>2</sub> layer to be greater than 17 Angstroms.

VanDover's specific application example is directed to a capacitor, which requires the thickness of the dielectric to be a function of the capacitance. However, VanDover expressly discloses that the dielectric can be used for MOSFET gate dielectrics (Col. 4, line 30).

Gardner discloses a MOS transistor with a TiO<sub>2</sub> gate dielectric, wherein a suitable thickness for the TiO<sub>2</sub> gate dielectric layer ranges from about 15 Angstroms to about 400 Angstroms (Gardner Col. 3, lines: 20-25).

It would have been obvious to one of ordinary skill in the art at the time of the invention to incorporate VanDover's dielectric material into a MOSFET gate dielectric with Gardner's dielectric thickness range since both dielectrics are composed of TiO<sub>2</sub> and since VanDover expressly discloses that the dielectric can be used for MOSFET gate dielectrics (Col. 4, line 30).

## Response to Arguments

Applicant's arguments filed 5/30/06 have been fully considered but they are not persuasive. Applicant argues that VanDover in view of Scobey does not disclose the

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limitation "wherein the TiOx layer doped with the lanthanide has an oxygen content supplemented".

Examiner disagrees. It is the Examiner's position that oxygen is a constituent of TiOx, and is therefore inherent that an oxygen content is supplemented during the formation process of the TiOx layer doped with the lanthanide (see above rejection). In fact, Applicant agrees that a TiOx layer inherently has an oxygen content, however, Applicant argues that the language "an oxygen content supplemented" means oxygen in excess to the oxygen content inherent in TiOx. This is not persuasive because the language "an oxygen content supplemented" cannot reasonably be limited to mean "in excess to the oxygen content already inherent in TiOx".

### Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Douglas M. Menz whose telephone number is 571-272-1877. The examiner can normally be reached on M-F 8-5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Bill Baumeister can be reached on 571-272-1722. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Dong My 9/3/06

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